

HARDROC ASIC

User Guide

DRAFT, March 19, 2007

I. Presentation :

The HaRDROC (Hadronic RPC ReadOut Chip) ASIC has been designed for the readout of the “Digital” Hadronic CALorimeter (DHCAL) that will be used in the International Linear Collider. .

1. DHCAL forseen detectors:

A **new generation of high precision detectors** is developed to be used in a very near future for the detector on the ILC lepton collider.

Such detectors are already under investigation all over the world. This takes place in the frame of the preparation for the International Linear Collider (ILC). The main aspect of the investigated detectors is their ability to allow the application of the so-called particle flow algorithms which consist of following the particle in each part of the whole detector and not only in the tracker as it used to be. Being able to follow a particle in the different sub-detectors will allow to chose the particle energy measurement in the sub-detector which provides the best energy resolution for the traced particle. This implies to conceive electromagnetic and hadronic calorimeters in a new manner. They should indeed provide not only very precise energy measurement but also strong tracking capacity.

To realise a hadronic calorimeter with tracking capacity, 3 options are currently under study:

- A hadronic calorimeter with a sensitive part based on plastic scintillating tiles associated to **SiPM** and using the same analogue electronics readout proposed for the electromagnetic calorimeter. The size of the plastic tiles are however large (3x3 cm²). A specific ASIC (**SPIROC**) is under design for the readout of such a detector
- A more granular detector concept using Glass Resistive Plate Chambers (GRPC) with pads of 1X1 cm² size. It will be made of planes of stainless steel making the absorber part of the calorimeter. Each stainless steel plane will be followed by a plane of an active medium. As active medium, two kinds of chambers are under investigation: the **Glass Resistive Plate Chamber (GRPC)** and the **MICROME GAS chamber (μ MEGAS)**.

HARDROC has been designed for the readout of GRPC or μ MEGAS.

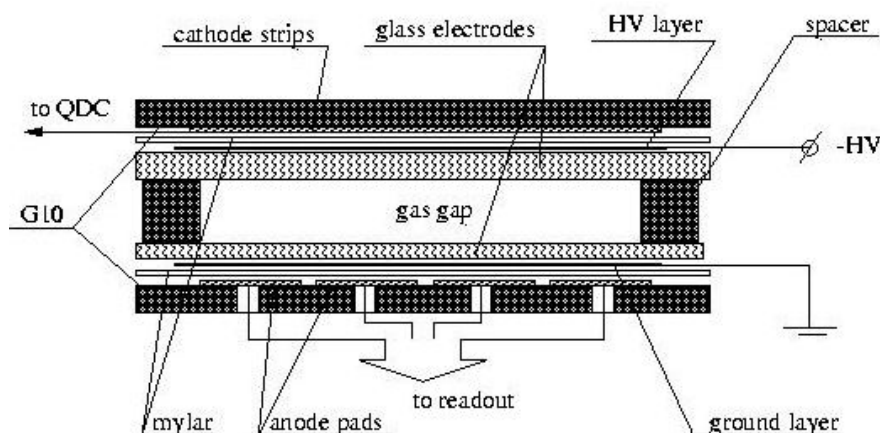


Figure 1: RPC design

II. HARDROC specifications:

An hadronic calorimeters of **very fine granularity** needs appropriate electronics readout. The number of **electronics channels ($4 \cdot 10^5 / \text{m}^2$)** is a new feature of hadronic calorimeter domain.

The **electronics readout system** is based on a semi-digital readout with two thresholds (2 bits readout). This is a compromise between the analogue solution of the German-Russian solution (SiPM) and the binary one proposed by the Americans. This compromise allows both good tracking and good energy measurement.

The new electronics readout is **intended to be embedded in the detector**. One important feature is the reduction of the power consumption. The huge number of electronic channels makes crucial such a reduction to **$10 \mu\text{Watt per channel}$** using the power pulsing scheme, possible thanks to the ILC bunch pattern: 1 ms of acquisition data for 199 ms of dead time.

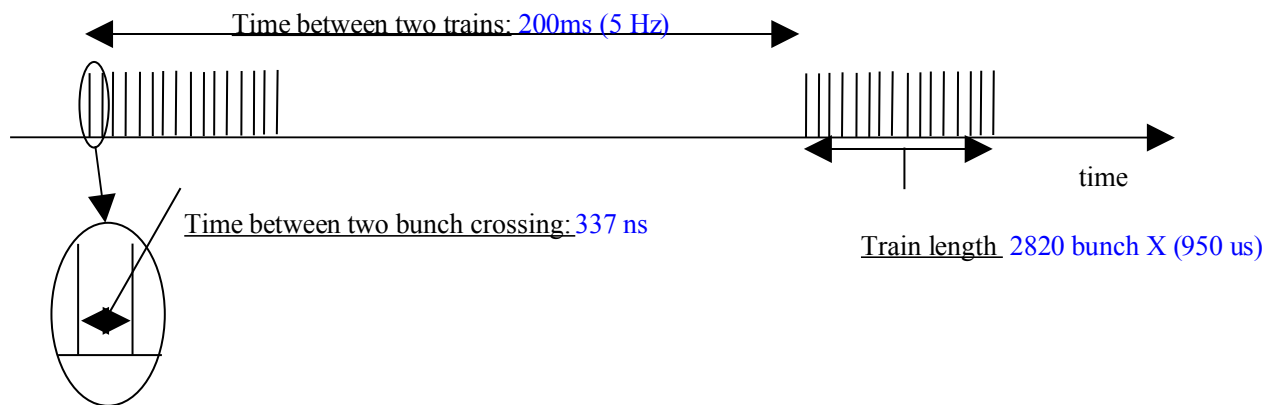


Figure 2: ILC bunch pattern

A prototype made of 40 planes of 70X70 cm² interleaved with absorber planes of stainless steel 1 cm thick will require 64X64X40 electronics channels. Because of the very high number of electronic channels, it is essential to limit the amount of the transmitted data and hence the recorded ones without losing information. To achieve this aim, the acquisition system will make use of zero suppression techniques and data concentrators for each detector plane. The data of each plane will then be transferred to computing unit through a USB device.

As the detector used is still not defined (RPC or GEM), the analog front-end of the HARDROC chip has to deal with several dynamic ranges and shaping. It services 64 inputs and provides a single serial data output.

HARDROC1 has been designed using the AMS SiGe 0.35 μm technology (Fig. 3). The package used is CQFP240. The area of the chip is 16mm². It has been submitted in Sept 2006 and received in December 2006.

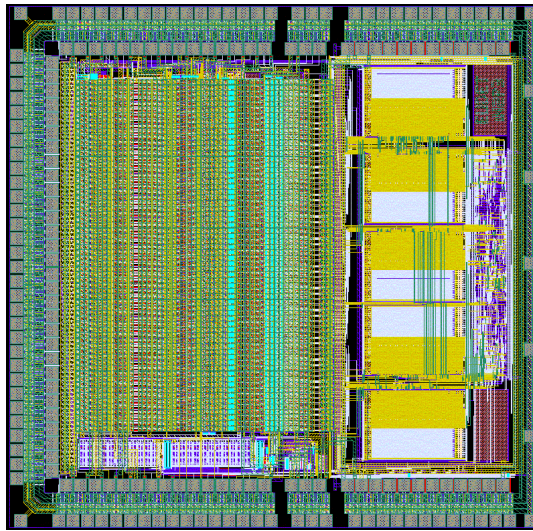


Figure 3: Layout of HARDROC1

Fig. 4 represents the bloc diagram of HARDROC1 with its main features. The chip has 64 “super common base” inputs, 1 serial output and a multiplexed charge output.

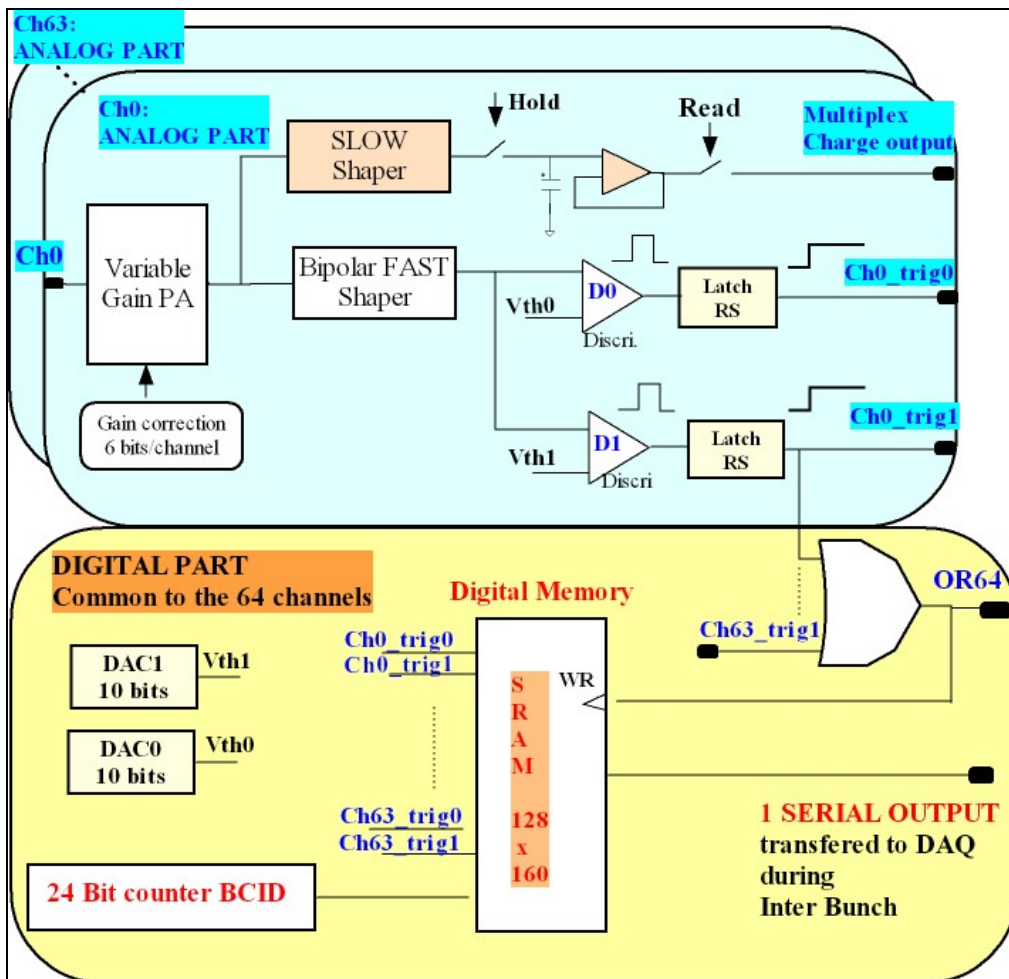


Figure 4: Simplified schematics of HARDROC1

Each channel is made of a variable gain preamplifier with low input tunable impedance (50-100 Ω), a low offset and a low bias current (20 μA) in order to minimize the cross talk. This variable gain allows adapting the gain depending on the detector choice, up to a factor 4 to an

accuracy of 6% with 6 bits. This gain tuning is also convenient to switch off a noisy channel. The amplified current feeds then two paths:

- A slow shaper path which consists in a CRRC² shaper and a Sample and Hold Widlar differential buffer. This S&H block stores the charge in a 2pF capacitor and delivers a multiplexed charge measurement with a 5 MHz readout speed.
- A fast (15ns) shaper path made of a CRRC bipolar shaper followed by 2 discriminators the thresholds of which are set by 2 internal 10 bit DACs.
- Each trigger output is latched to hold the state of the response until the end of the clock cycle. The trigger1 outputs (corresponding to $V_{th1} < V_{th0}$) are OR wired to generate an internal trigger used to start the memorization of the 128 trigger outputs as well as the Bunch Crossing Identification delivered by a 24 bit counter. Indeed, to reconstruct hits in the DAQ, the chip must provide an event ID for each hit. It's also possible to capture event data using an external trigger provided from outside the chip.
- All the biases are programmed through the Slow Control
- The chip is power pulsed to decrease the power consumption. 10μV/channel is targeted with a 1% beam duty cycle

III. HARDROC analog part :

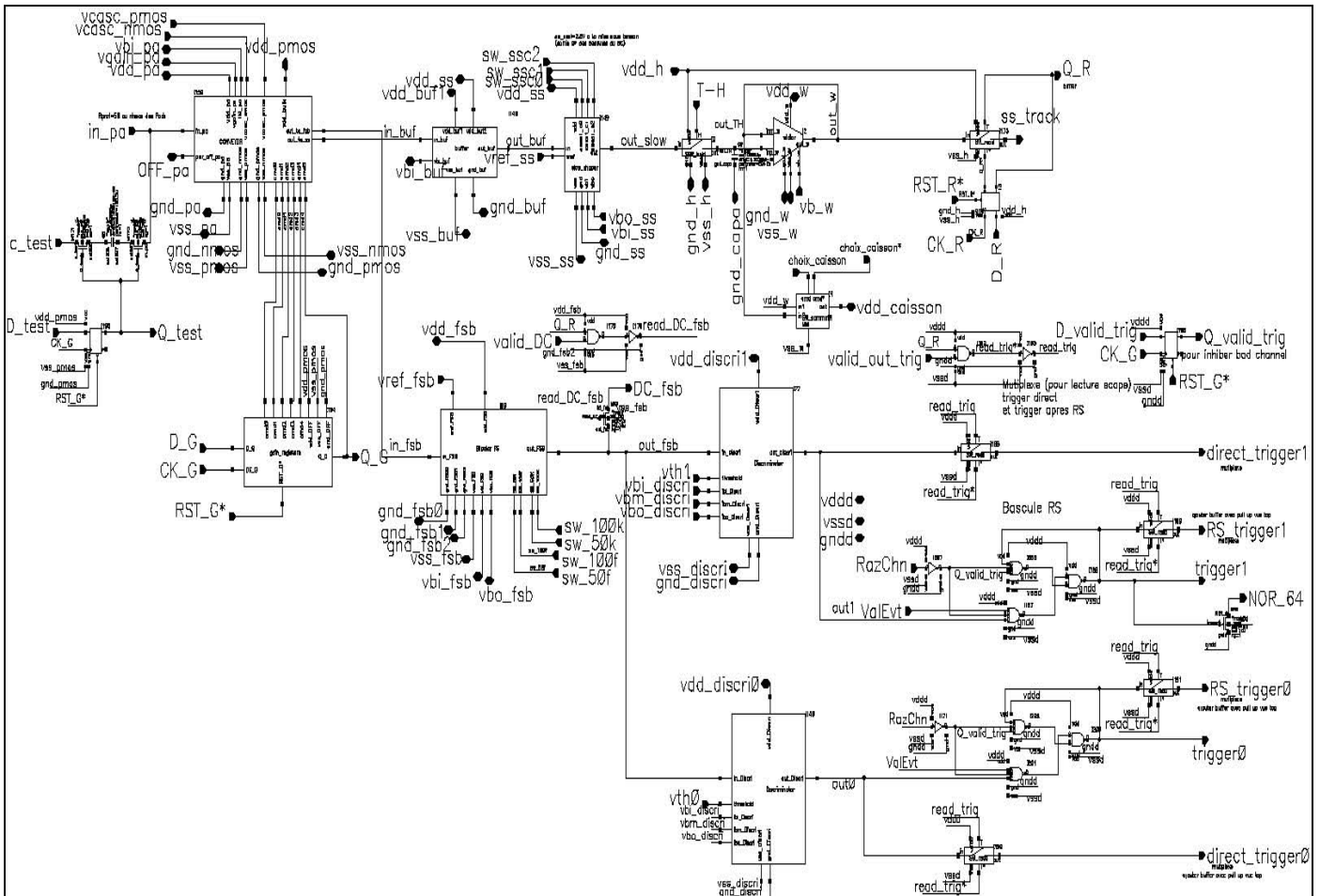
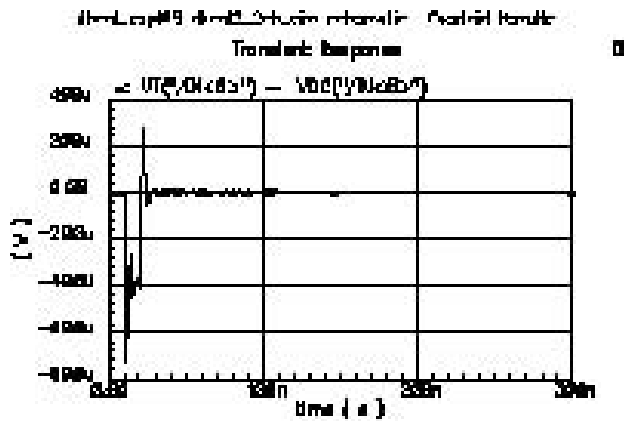
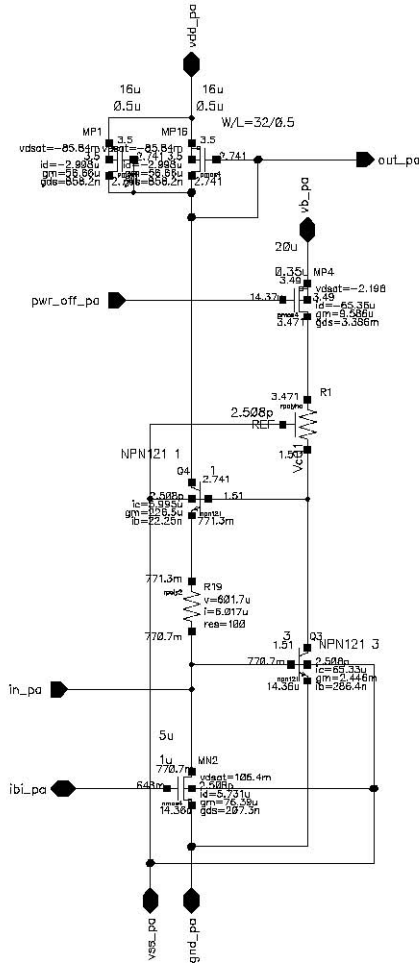


Figure 5: ONE CHANNEL (analog part)

1- Input Preamp: Super Common Base configuration

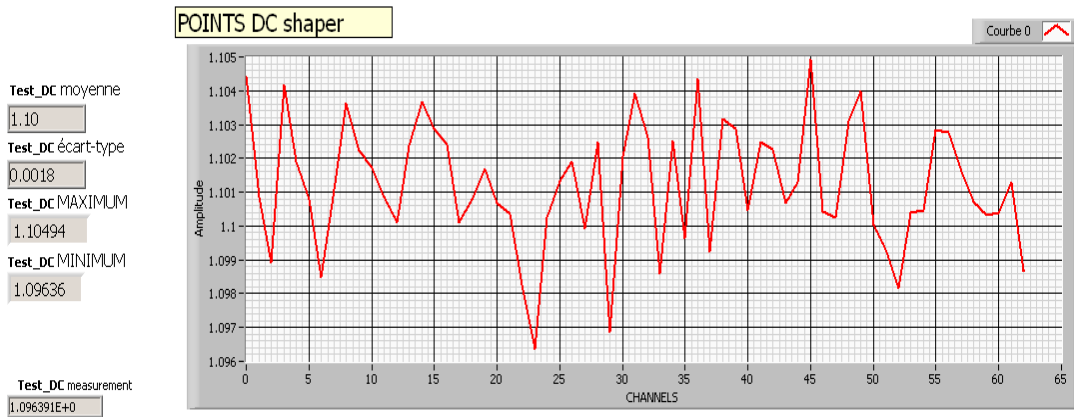
The input impedance of the SBC is given by: $Z_{in} = 1/g_{m1}g_{m2}R_c$ which is a low value resulting in small currents in the mirrors and thereby reducing the crosstalk.

The current source is made with a 39k resistor the noise of which is $\sqrt{\frac{4kT}{R}} = 0.65 \text{ pA} / \sqrt{\text{Hz}}$. A real current source would exhibit a noise of $2qI = 2 * 1.6 \cdot 10^{-19} \cdot 20 \cdot 10^{-6} = 2.5 \text{ pA} / \sqrt{\text{Hz}}$, which is not acceptable.



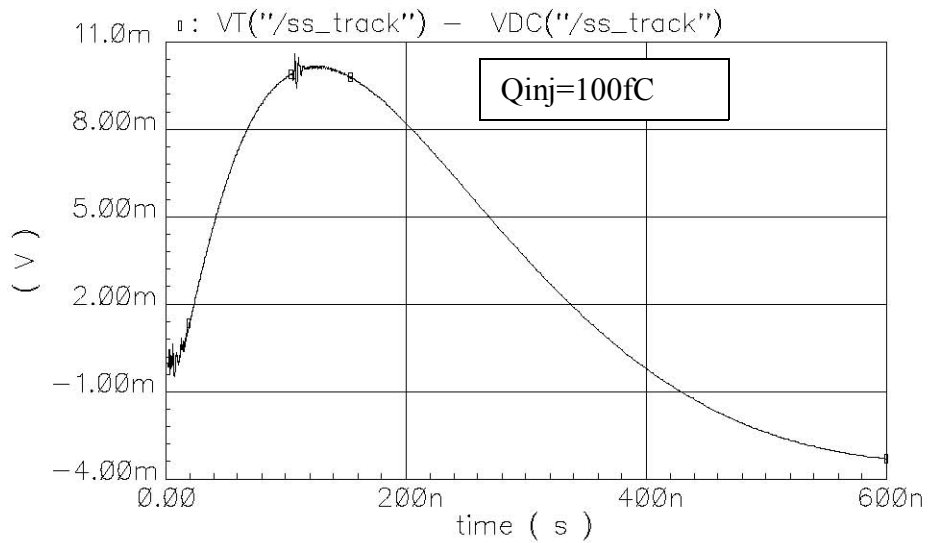
2- Slow channel

DC uniformity of the 64 channels: $\langle \diamond \rangle = 1.10\text{V}$ $\sigma = 1.8\text{mV}$

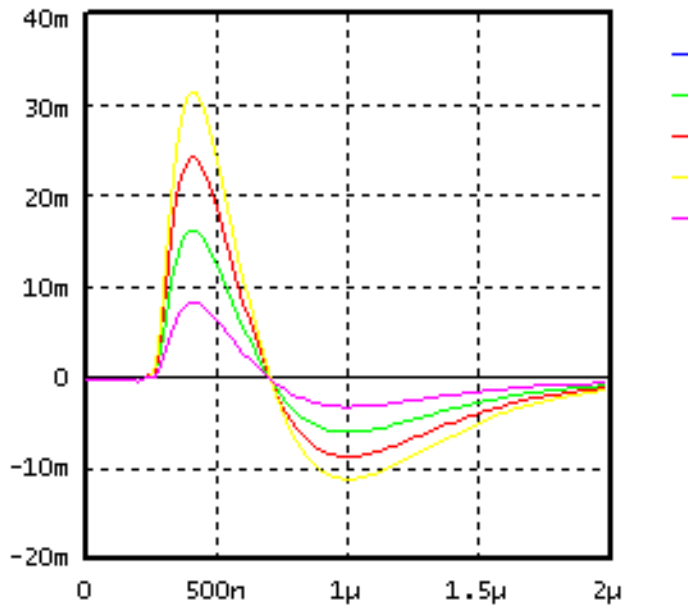


dhca1_sept06 dhca12_2ch_sim schematic : Overlaid Results

Transient Response



SS: out buffer Qinj=100fC G=1,2,3,4²

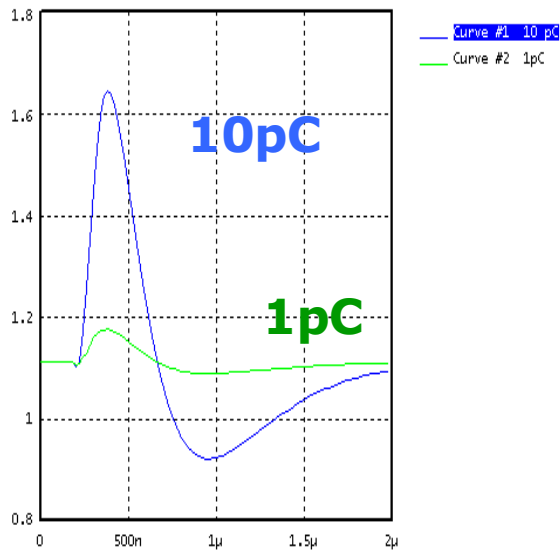


Qinj=100 fC (1V attenuated by 40dB in 10pF) :

Gain PA= 1	18.47 mV	tp=144 ns
G=2	16.51 mV	148 ns
G=3	24.44 mV	146ns
G=4	31.66mV	145ns

SS: Qinj=1pC, 10pC out.OTA_SS

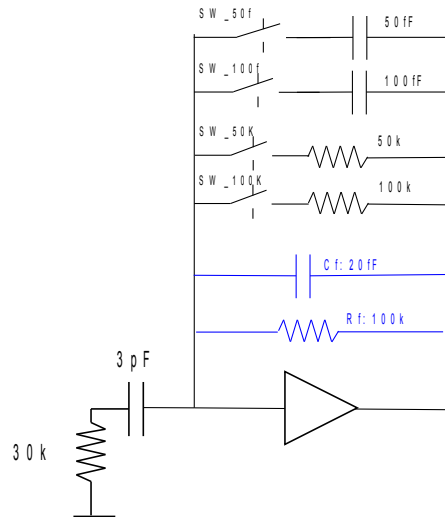
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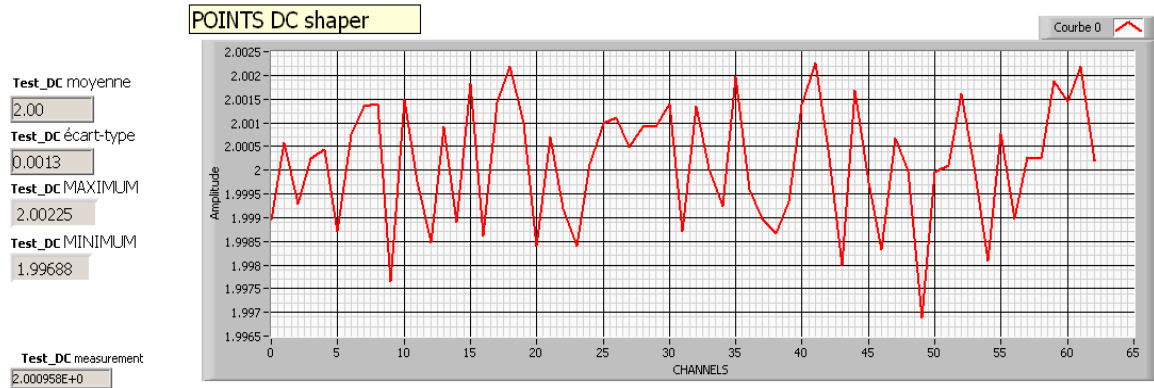
**DC level
≈ 1V**

3- Bipolar Fast shaper

Bipolar Fast Shaper

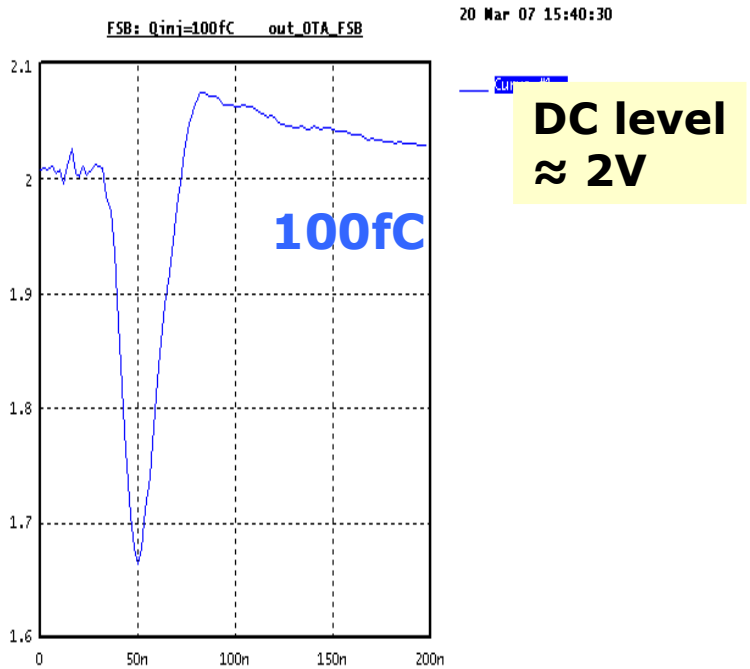
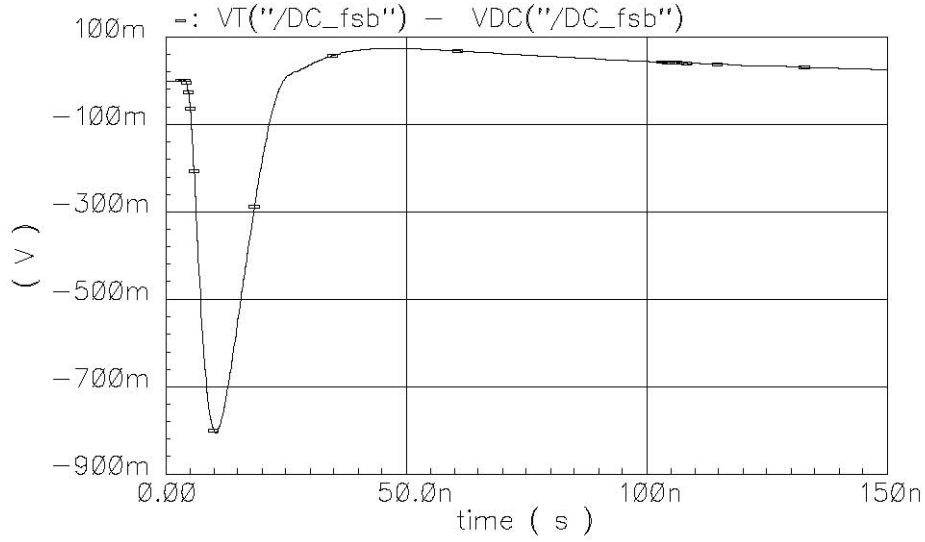


DC uniformity of the 64 channels: $\langle \rangle = 2.00V$ $\sigma = 1.3mV$



dhcal_sept06 dhcal2_2ch_sim schematic : Overlaid Results

Transient Response



■ 100fC \Rightarrow 350mV, $t_p=15ns$, ie 3.5mV/fC

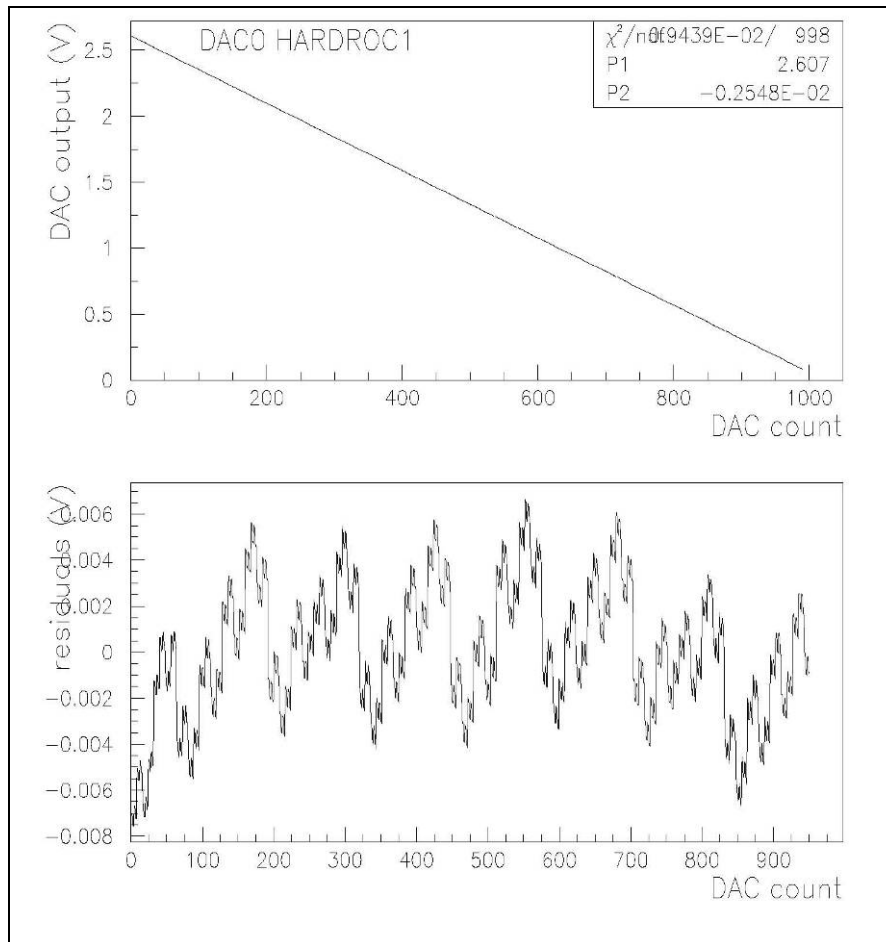
4- DAC

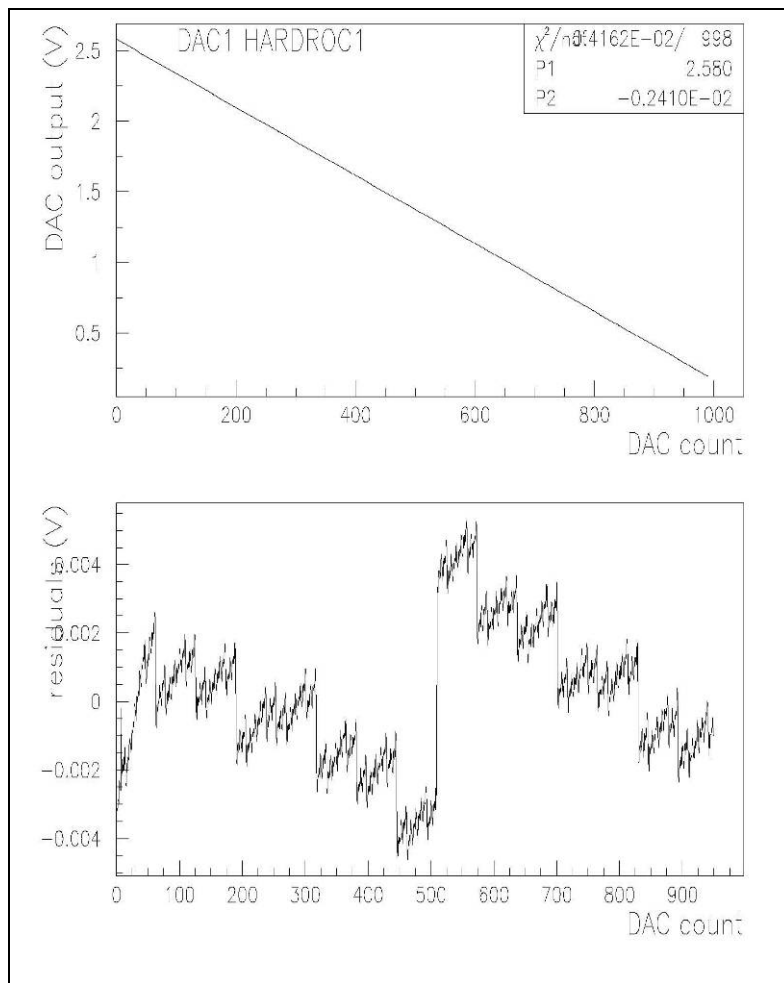
2 integrated DACs to deliver Threshold voltages

Residuals within ± 5 mV / 2.6V dynamic range.

INL= 0.2% (2LSB)

2.5 mV/UDAC





5- Discriminator

III. HARDROC digital part :

1- ANALOG-DIGITAL Interface

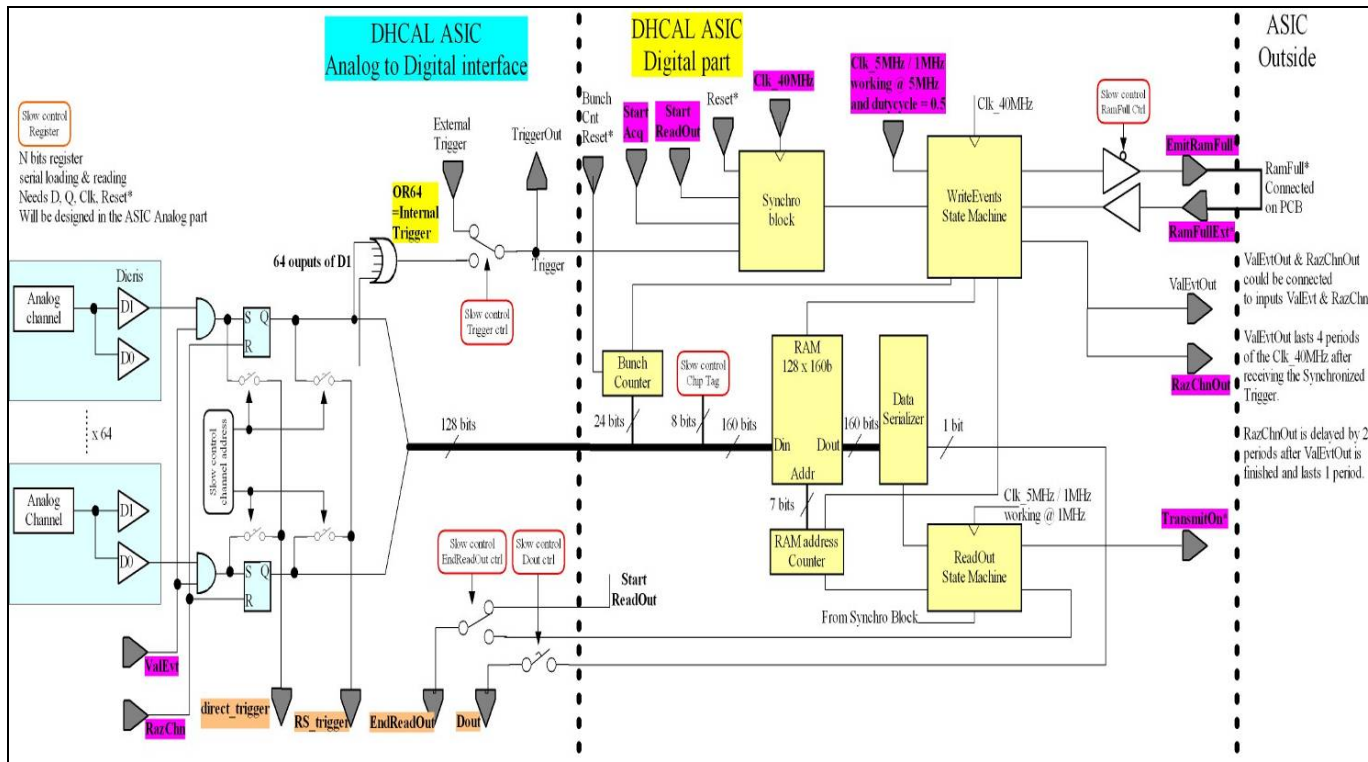


Figure 6: Interface between analog and digital part

DHCAL_v3

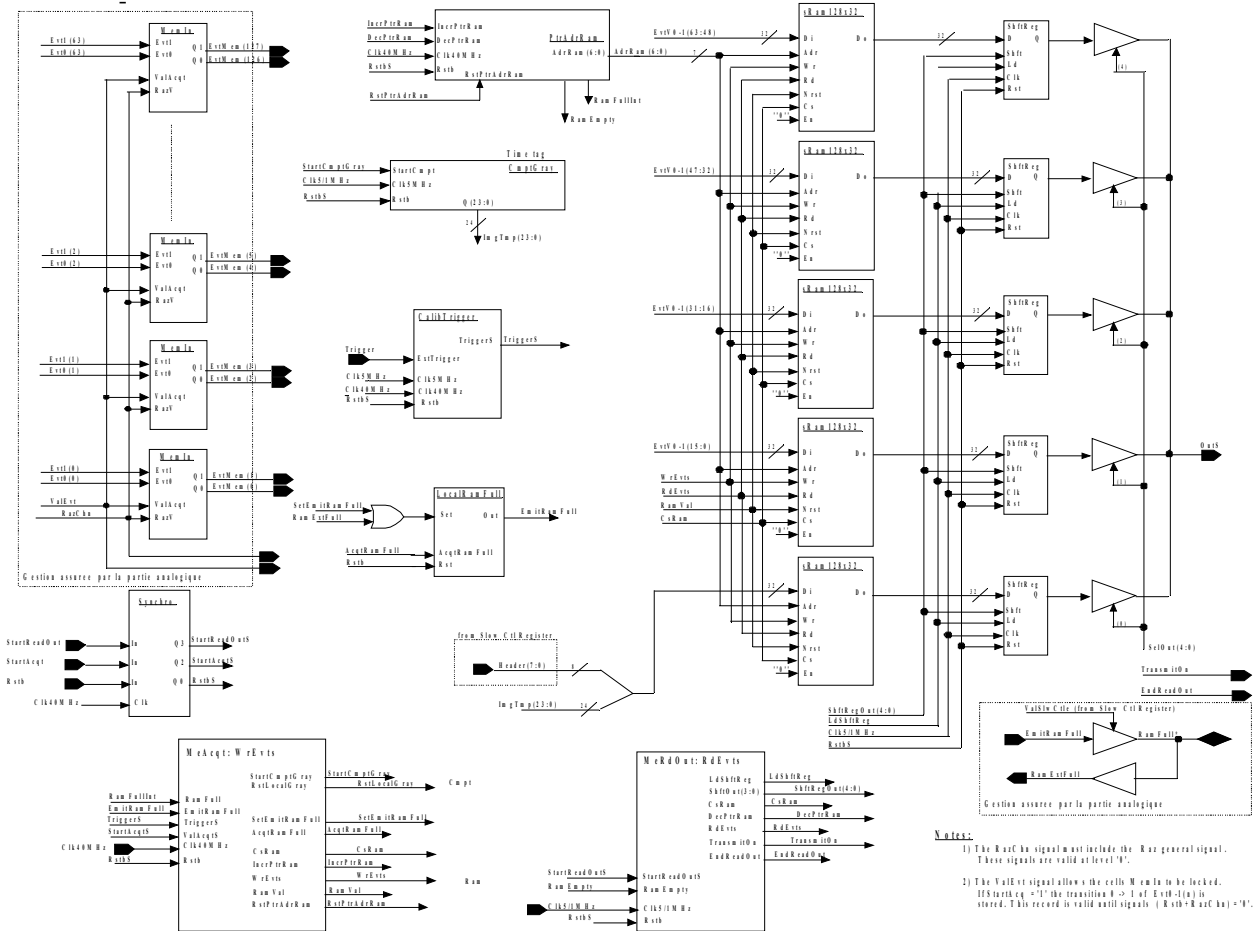
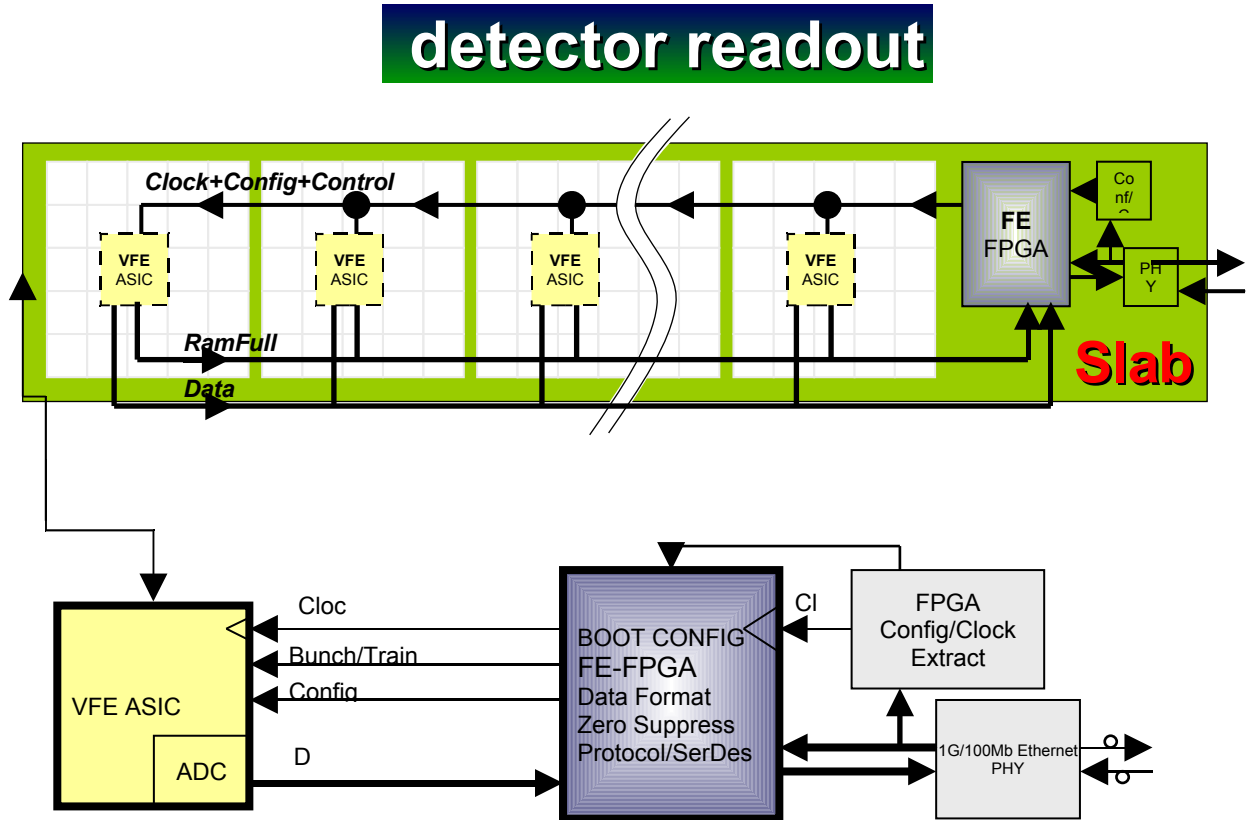


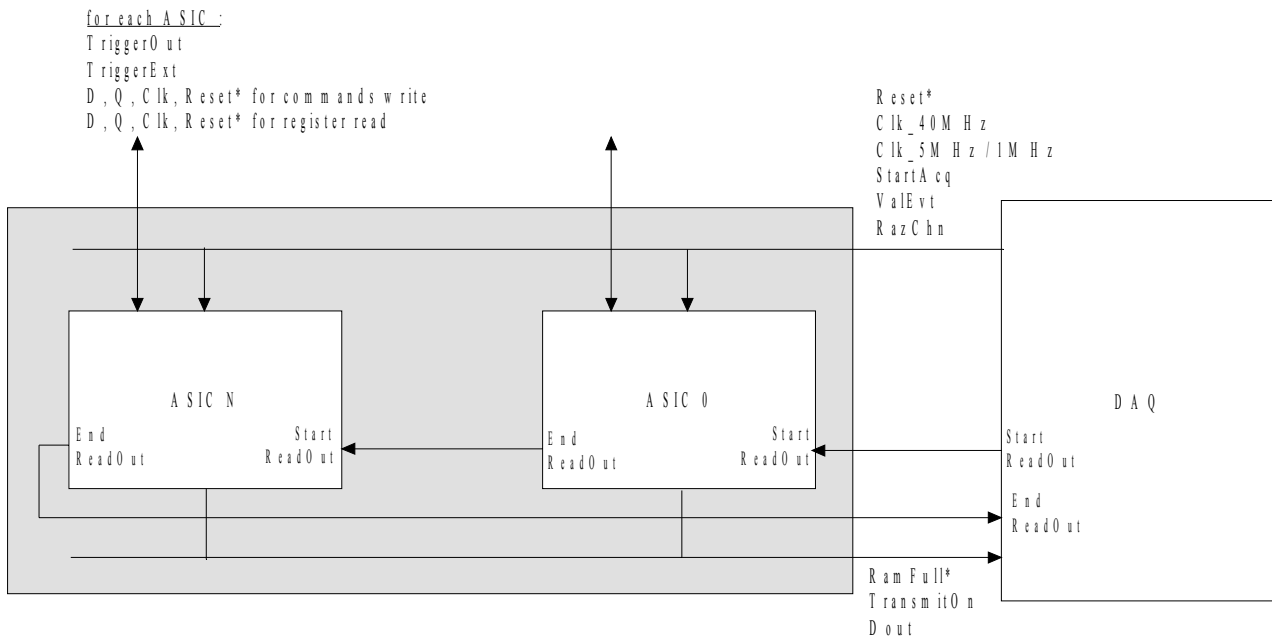
Figure 7: Digital part

1. Digital Front-end description :



There will be 16 64 ch ASICs/SLAB. To minimize the number of lines on the PCB, the ASICs are daisy chained.

DIGITAL SIGNALS



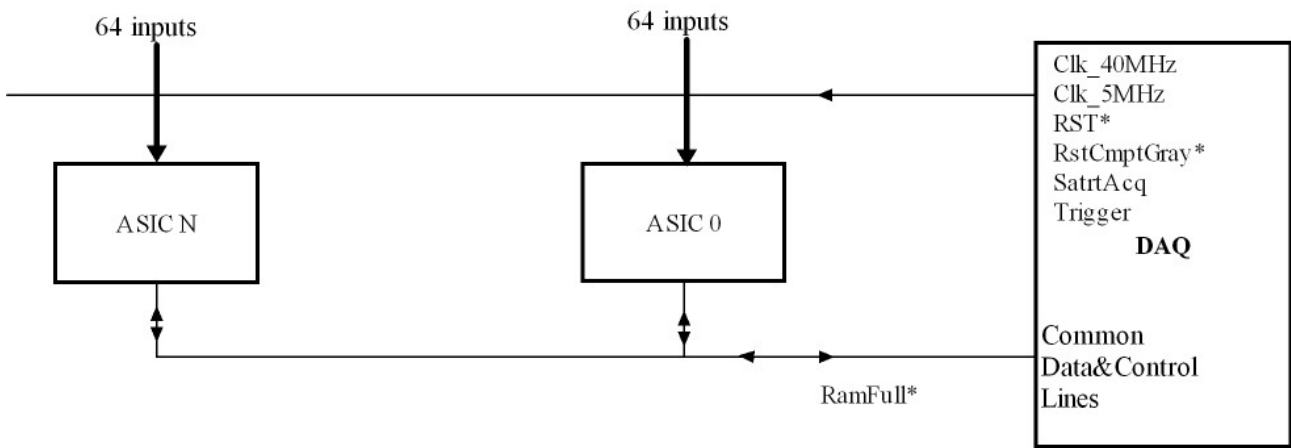
The following table lists the signals that will be routed on the PCB.

Signal name	INPUT/OUPUT	Valid on	Common	Adaptation	Single/Diff
Reset*	INPUT	LOW	YES	YES	SINGLE
Clk_5MHz / 1MHz	INPUT	RISING	YES	YES	DIFF
Clk_40MHz	INPUT	RISING	YES	YES	DIFF
StartAcq	INPUT	HIGH	YES	YES	SINGLE
ValEvt	INPUT	HIGH	YES	YES	DIFF
RazChn	INPUT	HIGH	YES	YES	DIFF
StartReadOut	INPUT	HIGH	NO	NO	SINGLE
EndReadOut	OUTPUT	HIGH	NO	NO	SINGLE
TransmitOn	OUTPUT	HIGH	YES	YES	SINGLE
Dout	OUTPUT	-	YES	YES	SINGLE
RamFull*	BIDIR	LOW	YES	YES	SINGLE
TriggerExt	INPUT	RISING	NO	NO	SINGLE
TriggerOut	OUTPUT	RISING	NO	NO	SINGLE

The DAQ provides the 40 MHz clock which is necessary for the state machin of the ASIC memory. The slow clock (5 or 1MHz) is used for the acquisition and the readout mode. TransmitOn, RamFull* and Dout are open collector signals.

Acquisition mode:

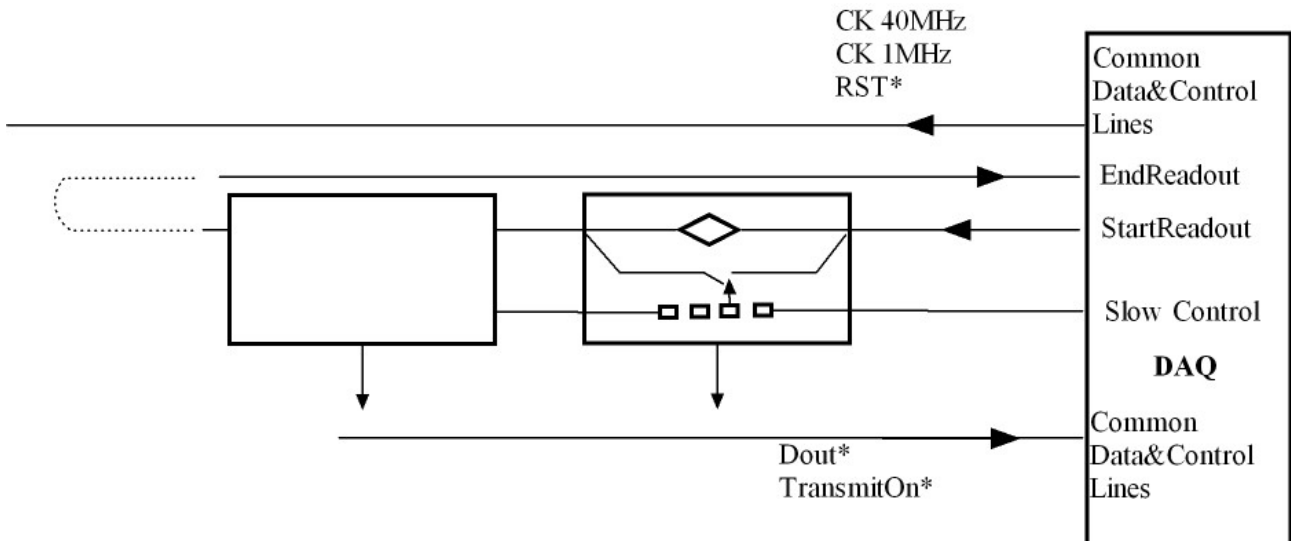
The StartAcq signal initiates the acquisition; The ValEvt signal (LVDS) is a validation window necessary to enable the latch of the triggers. Up to 128 events are stored in the memory. The acquisition is stopped when the RamFull signal is sent by one of the ASICs.



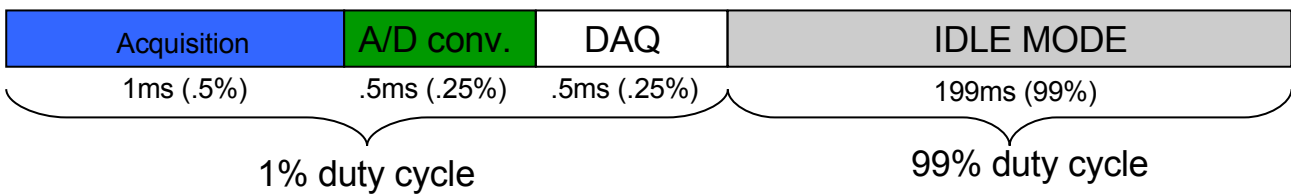
Readout mode:

The readout is made using a token ring mechanism initiated by the DAQ with the possibility to bypass a chip by slow control.

One data line is activated by each chip sequentially.



Timing:



IV. PINOUT :

pin number	pin name	connect to	DC voltage	DC current	Bias
1	in<2>	detector	0.8V		
29	in<30>	detector			
30	in<31>	detector			
31	gnd_pa	gnda			
32	in<32>	detector			
60	in<60>	detector			
61	in<61>	detector			
62	vssi				
63	in<62>	detector			
64	in<63>	detector			
65	gnd_pa	gnda			
66	vdd_pad		3,5V		
67	vdd_pa	vdda	3.5V		connected to 231
68	ctest				
69	gnd_nmos				
70	vcasc_pmos		1V		divider 1K,2.5K
71	vssa				
72	vcasc_nmos		1,5V		divider 1.5K,2K
73	vdd_buf1				
74	gnd_buf	gnda			
75	vdd_pmos				
76	ibi_otadac		0.8V	178uA	100K to gnd_bg
77	vdd_dac				
78	ibo_otadac		0.6V	28uA	1K to gnd_bg
79	gnd_dac				
80	Q_R				LVTTTL ASIC input
81	hold				LVTTTL ASIC input
82	vcasc_dac		1V		divider (10K,25K)
83	D_R				LVTTTL ASIC input
84	iref_dac	External 68K to gnd			150K to v_bg
85	CK_R				LVTTTL ASIC input
86	vref_otadac		2V		(200K,50K) to v_bg
87	rst_R*				LVTTTL ASIC input
88	vdd_bg				
89	pwr_on_dac				Slow Control
90	ibi_otabg		2.6V	25uA	100K to gnd_bg
91	gnd_bg				
92	ibo_otabg		2,5V	2.5mA	1K to gnd_bg
93	vssa				
94	vth0				
95	vdd_d0				

96	gnd_d				
97	vdd_d1				
98	vth1				
99	vssm				
100	vssd				
101	gndd				
102	vddd2				
103	vddd				
104	ib_rec		0.8V	106uA	25K to vddd
105	<i>pwr_on_d</i>				LVTTTL ASIC input
106	<i>Val_Evt</i>				LVDS ASIC input (from DAQ)
107	<i>Val_Evt*</i>				
108	<i>out_RazChn_int</i>				LVTTTL ASIC output
109	<i>rst*</i>				LVTTTL ASIC input
110	<i>Raz_Chn</i>				LVDS ASIC input
111	<i>Raz_Chn*</i>				
112	<i>CK_40M</i>				LVDS output (from DAQ)
113	<i>CK_40M*</i>				
114	<i>CK_5M</i>				LVDS output (1/8 de 40M)
115	<i>CK_5M*</i>				
116	<i>out_trig_int</i>				LVTTTL ASIC output (NOR64 or ext)
117	<i>trigger_ext</i>				LVTTTL ASIC input
118	<i>End_ReadOut</i>				LVTTTL ASIC output
119	<i>Start_ReadOut</i>				LVTTTL ASIC input
120	NC1				
121	<i>Start_Acq</i>				LVTTTL ASIC input
122	vddd2				
123	<i>rst_counter*</i>				LVTTTL ASIC input
124	NC				
125	vssd				
126	NC				
127	vssd				
128	NC				
129	vssd	gndd			
130	NC				
131...	NC				
...148	NC				
149	vssd				
150	NC				
151	vssd				
152...	NC				
...174	NC				
175	vssd				
176	NC				
177	vssd				

178	NC				
179	vddd2				
180	NC				
181	rtn	rtn			DC=0 ou 0,5V
182	RamFull_ext				LVTTL ASIC input
183	RamFull*				OC ASIC output : LVTTL (testboard)
184	RamFull_007				Test point (Not Connected to DAQ)
185	Dout*				OC ASIC output : LVTTL (testboard)
186	Dout_007				Test point (NC to DAQ)
187	TransmitOn*				OC ASIC output : LVTTL (testboard)
188	TransmitOn_007				Test point (NC to DAQ)
189	rst_SC*				LVTTL ASIC input
190	Q_SC				LVTTL ASIC input
191	D_SC				LVTTL ASIC input
192	out_RS_trig1				LVTTL ASIC output (to DAQ)
193	CK_SC				LVTTL ASIC input
194	out_RS_trig0				LVTTL ASIC output (to DAQ)
195	pwr_on_ss				LVTTL ASIC input
196	out_trig1				LVTTL ASIC output (Lemo)
197	pwr_on_a				LVTTL ASIC input
198	out_trig0				LVTTL ASIC output (Lemo)
199	vddd				
200	vddd2				
201	gndd				
202	vssd				
203	vdd_d2	guard ring for discriminators			
204	ibi_d		0.8V	27uA	100K to vdda
205	ibm_d		2.5V	25uA	100K to gnd
206	ibo_d				100K to gnd
207	gnd_d				
208	vssm				
209	vssa				
210	v_bg		2,5V		
211	gnd_fsb1				
212	out_fsb	R115=1K instead of 10K			To decrease Slew Rate
213	vref_fsb	External 2.7K	2V		2.7K external in // (2.2K,300) to v_bg
214	ibo_fsb		2.3V	22uA	100k to gnd
215	vdd_fsb				
216	ibi_fsb		2.4V	41uA	60K to gnd
217	gnd_fsb0				
218	out_Q	R115=1K instead of 10K			To decrease Slew Rate
219	vdd_w				
220	ib_otaq	External 2K to gnd	1V	450uA	5592 to vdd
221	gnd_w				
222	gnd_capa				

223	EN_otag				
224	ib_w		0.8V	11uA	25K to vdd
225	gnd_ss				
226	ibo_ss		0.8V	11uA	25k to vdd
227	vdd_ss				
228	ibi_ss		0.8V	11uA	25K to vdd
229	vref_ss		1,1V		(11K,14K) to v_bg
230	ib_buf				50K to vdd
231	gnd_nmos				
232	vgain_pa		3.5V		300//300 to vdd
233	vdd_pa				
234	ib_pa		0.7V	6uA	500K to vdd
235	vssa				
236	vssi				
237	gnd_pa				
238	in<0>	detector			
239	in<1>	detector			
240	vssi				

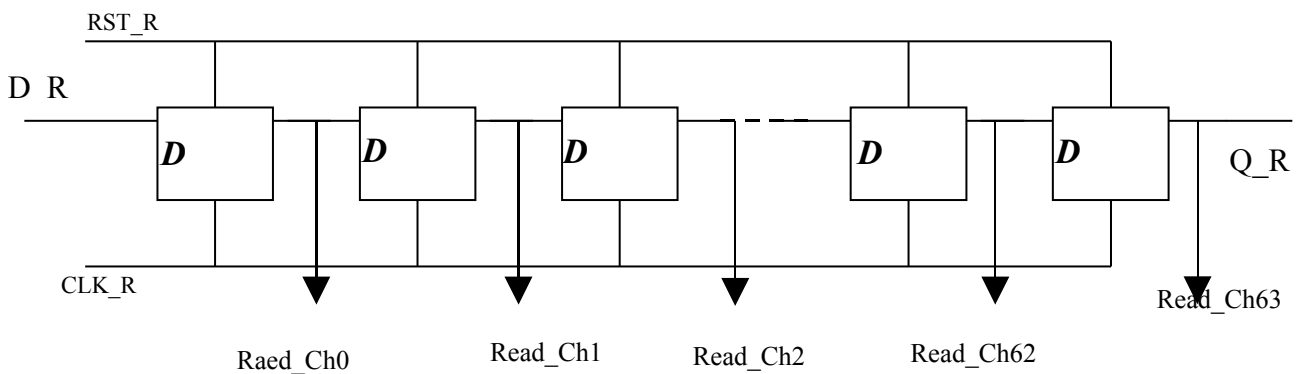
V. READ and SLOW CONTROL REGISTERS:

2 shift registers are integrated:

- One Read register to select (multiplex) one channel among the 64.

RST*:

0 => Reset all the registers D to 0 → empty the shift register → disable the output



- One slow control register to load serially the 571 slow controls parameters:

CELL	BIT#	BIT NAME
Dig_bias	1	EN_RamFull
	2	EN_Dout
	3	EN_TransmitOn
	4	EN_out_discr

	5	Header 0
	6	Header 1
	7	Header 2
	8	Header 3
	9	Header 4
	10	Header 5
	11	Header 6
	12	Header 7
	13	bypass_chip
	14	EN_out_trig_int
	15	EN_trig_int
	16	EN_trig_ext
	17	EN_out_raz_int
	18	EN_raz_int
	19	EN_raz_ext
	20	Not used
One_Channel0	21	Valid_trig channel 0
One_Channel1	22	Valid_trig channel 1

One_Channel63	84	Valid_trig channel 63
dual_dac_10bits	85	B0 0
	86	B0 1

	94	B0 9
	95	B1 0
	96	B1 1

	104	B1 9
	105	ON_otadac
	106	ON_dac
	107	ON_otabg
One_Channel0	108	Ctest ch 0
One_Channel1	109	Ctest ch 1

One_Channel63	171	Ctest ch 63

One_Channel0	172	Preamp gain cmd0 ch 0
	173	Preamp gain cmd1 ch 0
	174	Preamp gain cmd2 ch 0
	175	Preamp gain cmd3 ch 0
	176	Preamp gain cmd4 ch 0
	177	Preamp gain cmd5 ch 0
One_Channel1	178	Preamp gain cmd0 ch 1
	179	Preamp gain cmd1 ch 1

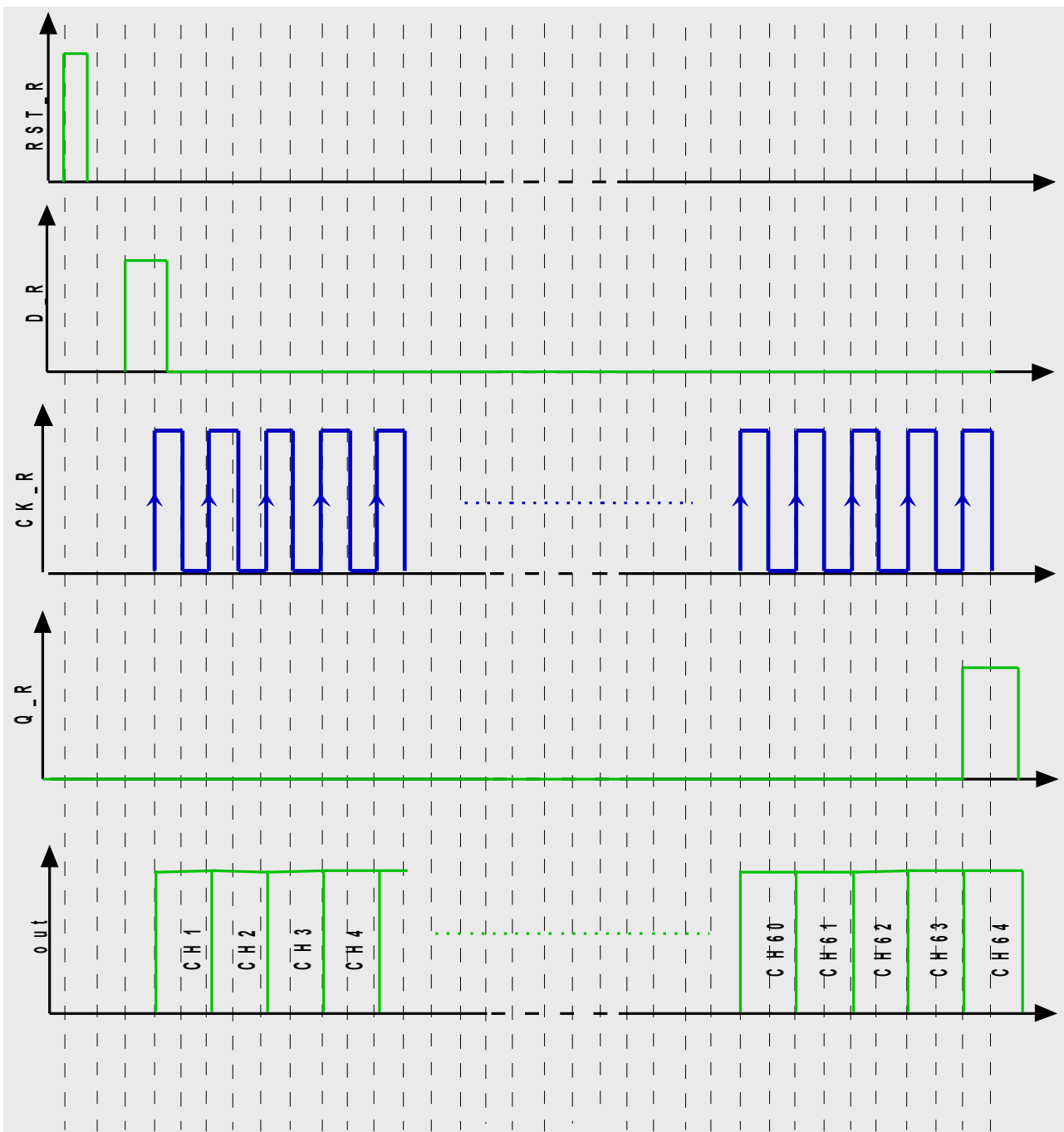
	183	Preamp gain cmd5 ch 1
One_Channel2	184	Preamp gain cmd0 ch 2
	185	Preamp gain cmd1 ch 2

	189	Preamp gain cmd5 ch 2

One_Channel63	550	Preamp gain cmd0 ch63
	551	Preamp gain cmd0 ch63

	555	Preamp gain cmd0 ch63
CELL	BIT#	BIT NAME
Bias	556	ON_pa
	557	ON_buf
	558	ON_ss
	559	ON_w
	560	ON_otaq
	561	ON_fsb
	562	ON_discri
	563	Valid_DC
	564	Sw_50f

	565	Sw_100f
	566	Sw_100k
	567	Sw_50k
	568	Choix_caisson
	569	Sw_ssc2
	570	Sw_ssc1
	571	Sw_ssc0



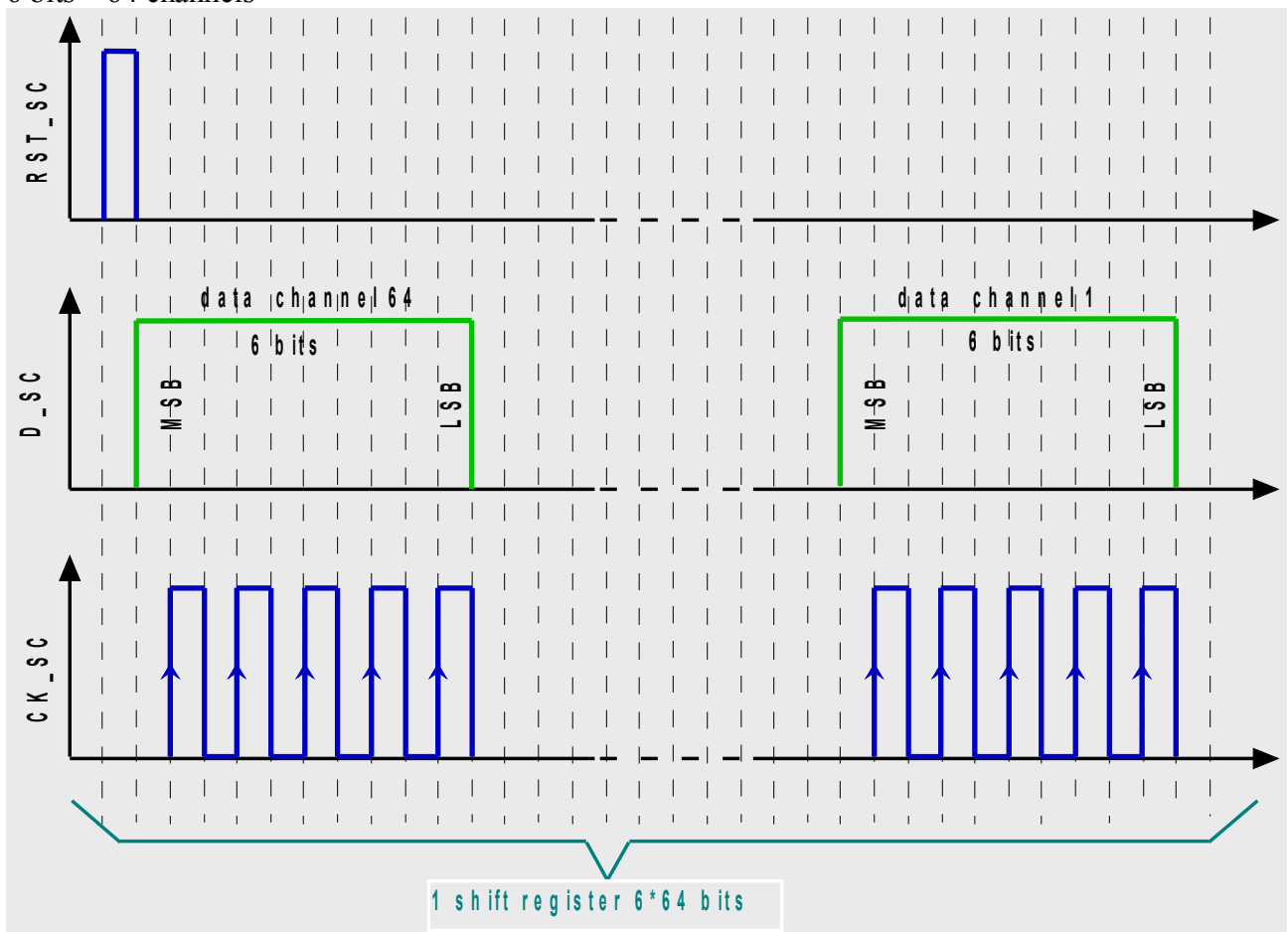
SC register :

Gain value serial loading

Reset gain register: RST_SC*

D_SC, Q_SC, CK_SC

6 bits * 64 channels



DAC value serial loading

D_DAC, Q_DAC, CK_DAC

2 DACs, 10 bits per DAC

